

# IRHF57034 (JANSR2N7492T2)

PD-93791G

**Radiation Hardened Power MOSFET  
Thru-Hole TO-205AF (TO-39)  
60V, 12A, N-channel, R5 Technology**

## Features

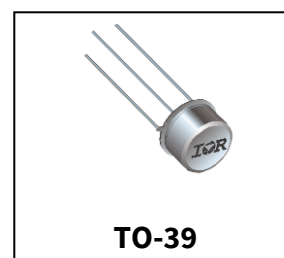
- Single event effect (SEE) hardened
- Low  $R_{DS(on)}$
- Repetitive avalanche ratings
- Dynamic  $dv/dt$  ratings
- Simple drive requirements
- Hermetically sealed
- ESD rating: Class 1C per MIL-STD-750, Method 1020

## Potential Applications

- DC-DC converter
- Motor drives
- Thermal management

## Product Summary

- $BV_{DSS}$ : 60V
- $I_D$ : 12A
- $R_{DS(on),max}$ : 48m $\Omega$
- $Q_{G,max}$ : 40nC
- REF: MIL-PRF-19500/701



## Product Validation

Qualified to JANS screening flow according to MIL-PRF-19500 for space applications

## Description

IR HiRel R5 technology provides high performance power MOSFETs for space applications. This technology has over a decade of proven performance and reliability in satellite applications. These devices have been characterized for both Total Dose and Single Event Effects (SEE). The combination of low  $R_{DS(on)}$  and low gate charge reduces the power losses in switching applications such as DC to DC converters and motor control. These devices retain all of the well-established advantages of MOSFETs such as voltage control, fast switching and temperature stability of electrical parameters.

## Ordering Information

**Table 1**      **Ordering options**

Part number	Package	Screening Level	TID Level
IRHF57034	TO-39	COTS	100 krad(Si)
JANSR2N7492T2	TO-39	JANS	100 krad(Si)
IRHF53034	TO-39	COTS	300 krad(Si)
JANSF2N7492T2	TO-39	JANS	300 krad(Si)
IRHF54034	TO-39	COTS	500 krad(Si)
JANSG2N7792T2	TO-39	JANS	500 krad(Si)

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## Absolute Maximum Ratings

## 1 Absolute Maximum Ratings

Table 2 Absolute Maximum Ratings (Pre-Irradiation)

Symbol	Parameter	Value	Unit
$I_{D1} @ V_{GS} = 12V, T_C = 25^{\circ}C$	Continuous Drain Current	12*	A
$I_{D2} @ V_{GS} = 12V, T_C = 100^{\circ}C$	Continuous Drain Current	9.5	A
$I_{DM} @ T_C = 25^{\circ}C$	Pulsed Drain Current <sup>1</sup>	48	A
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	25	W
	Linear Derating Factor	0.2	W/°C
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy <sup>2</sup>	270	mJ
$I_{AR}$	Avalanche Current <sup>1</sup>	12	A
$E_{AR}$	Repetitive Avalanche Energy <sup>1</sup>	2.5	mJ
$dv/dt$	Peak Diode Reverse Recovery <sup>3</sup>	9.6	V/ns
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C
	Lead Temperature	300 (0.063 in. /1.6 mm from case for 10s)	
	Weight	0.98 (Typical)	

\* Current is limited by package

<sup>1</sup> Repetitive Rating; Pulse width limited by maximum junction temperature.<sup>2</sup>  $V_{DD} = 25V$ , starting  $T_J = 25^{\circ}C$ ,  $L = 3.74mH$ , Peak  $I_L = 12A$ ,  $V_{GS} = 12V$ <sup>3</sup>  $I_{SD} \leq 12A$ ,  $di/dt \leq 244A/\mu s$ ,  $V_{DD} \leq 60V$ ,  $T_J \leq 150^{\circ}C$

## Device Characteristics

## 2 Device Characteristics

## 2.1 Electrical Characteristics (Pre-Irradiation)

Table 3 Static and Dynamic Electrical Characteristics @  $T_j = 25^\circ\text{C}$  (Unless Otherwise Specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	60	—	—	V	$V_{GS} = 0V, I_D = 1.0mA$
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.062	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 1.0mA$
$R_{DS(on)}$	Static Drain-to-Source On-State Resistance	—	—	48	m $\Omega$	$V_{GS} = 12V, I_{D2} = 9.5A^1$
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 1mA$
$G_{fs}$	Forward Transconductance	12	—	—	S	$V_{DS} = 15V, I_{D2} = 9.5A^1$
$I_{DSS}$	Zero Gate Voltage Drain Current	—	—	10	$\mu A$	$V_{DS} = 48V, V_{GS} = 0V$
		—	—	25		$V_{DS} = 48V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Leakage Forward	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Leakage Reverse	—	—	-100		$V_{GS} = -20V$
$Q_G$	Total Gate Charge	—	—	40	nC	$I_{D1} = 12A$
$Q_{GS}$	Gate-to-Source Charge	—	—	10		$V_{DS} = 30V$
$Q_{GD}$	Gate-to-Drain ('Miller') Charge	—	—	15		$V_{GS} = 12V$
$t_{d(on)}$	Turn-On Delay Time	—	—	25	ns	$I_{D1} = 12A^{**}$ $V_{DD} = 30V$ $R_G = 7.5\Omega$ $V_{GS} = 12V$
$t_r$	Rise Time	—	—	100		
$t_{d(off)}$	Turn-Off Delay Time	—	—	35		
$t_f$	Fall Time	—	—	30		
$L_s + L_D$	Total Inductance	—	7.0	—	nH	Measured from Drain lead (6mm / 0.25 in from package) to Source lead (6mm/ 0.25 in from package) with Source wire internally bonded from Source pin to Drain pin
$C_{iss}$	Input Capacitance	—	1160	—	pF	$V_{GS} = 0V$
$C_{oss}$	Output Capacitance	—	530	—		$V_{DS} = 25V$
$C_{rss}$	Reverse Transfer Capacitance	—	18	—		$f = 1.0MHz$

\*\* Switching speed maximum limits are based on manufacturing test equipment and capability.

<sup>1</sup> Pulse width  $\leq 300 \mu s$ ; Duty Cycle  $\leq 2\%$

## Device Characteristics

## 2.2 Source-Drain Diode Ratings and Characteristics (Pre-Irradiation)

Table 4 Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	12	A	
I <sub>SM</sub>	Pulsed Source Current (Body Diode) <sup>1</sup>	—	—	48	A	
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.5	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 12A, V <sub>GS</sub> = 0V <sup>2</sup>
t <sub>rr</sub>	Reverse Recovery Time	—	—	100	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 12A, V <sub>DD</sub> ≤ 25V di/dt = 100A/μs <sup>2</sup>
Q <sub>rr</sub>	Reverse Recovery Charge	—	214	—	nC	
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

## 2.3 Thermal Characteristics

Table 5 Thermal Resistance

Symbol	Parameter	Min.	Typ.	Max.	Unit
$R_{\theta JC}$	Junction-to-Case	—	—	5.0	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-Ambient (Typical Socket Mount)	—	—	175	

## 2.4 Radiation Characteristics

IR HiRel radiation hardened MOSFETs are tested to verify their radiation hardness capability. The hardness assurance program at IR HiRel is comprised of two radiation environments. Every manufacturing lot is tested for total ionizing dose (per notes 3 and 4) using the TO-3 package. Both pre- and post-irradiation performance are tested and specified using the same drive circuitry and test conditions in order to provide a direct comparison.

## 2.4.1 Electrical Characteristics — Post Total Dose Irradiation

Table 6 Electrical Characteristics @  $T_J = 25^\circ\text{C}$ , Post Total Dose Irradiation <sup>3, 4</sup>

Symbol	Parameter	Up to 500 krad (Si) <sup>5</sup>		Unit	Test Conditions
		Min.	Max.		
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	60	—	V	$V_{GS} = 0\text{V}$ , $I_D = 1.0\text{mA}$
$V_{GS(th)}$	Gate Threshold Voltage	2.0	4.0	V	$V_{DS} = V_{GS}$ , $I_D = 1.0\text{mA}$
$I_{GSS}$	Gate-to-Source Leakage Forward	—	100	nA	$V_{GS} = 20\text{V}$
	Gate-to-Source Leakage Reverse	—	-100		$V_{GS} = -20\text{V}$
$I_{DSS}$	Zero Gate Voltage Drain Current	—	10	$\mu\text{A}$	$V_{DS} = 48\text{V}$ , $V_{GS} = 0\text{V}$
$R_{DS(on)}$	Static Drain-to-Source On-State Resistance (TO-3) <sup>2</sup>	—	34	$\text{m}\Omega$	$V_{GS} = 12\text{V}$ , $I_{D2} = 9.5\text{A}$
$R_{DS(on)}$	Static Drain-to-Source On-State Resistance (TO-39) <sup>2</sup>	—	48	$\text{m}\Omega$	$V_{GS} = 12\text{V}$ , $I_{D2} = 9.5\text{A}$
$V_{SD}$	Diode Forward Voltage	—	1.5	V	$V_{GS} = 0\text{V}$ , $I_F = 12\text{A}$

<sup>1</sup> Repetitive Rating; Pulse width limited by maximum junction temperature.

<sup>2</sup> Pulse width  $\leq 300\text{ }\mu\text{s}$ ; Duty Cycle  $\leq 2\%$

<sup>3</sup> Total Dose Irradiation with  $V_{GS}$  Bias.  $V_{GS} = 12\text{V}$  applied and  $V_{DS} = 0$  during irradiation per MIL-STD-750, Method 1019, condition A.

<sup>4</sup> Total Dose Irradiation with  $V_{DS}$  Bias.  $V_{DS} = 48\text{V}$  applied and  $V_{GS} = 0$  during irradiation per MIL-STD-750, Method 1019, condition A.

<sup>5</sup> Part numbers IRHF57034 (JANSR2N7492T2), IRHF53034 (JANSF2N7492T2) and IRHF54034 (JANSR2N7492T2)

## IRHF57034 (JANSR2N7492T2)

### Radiation Hardened Power MOSFET Thru-Hole (TO-39)

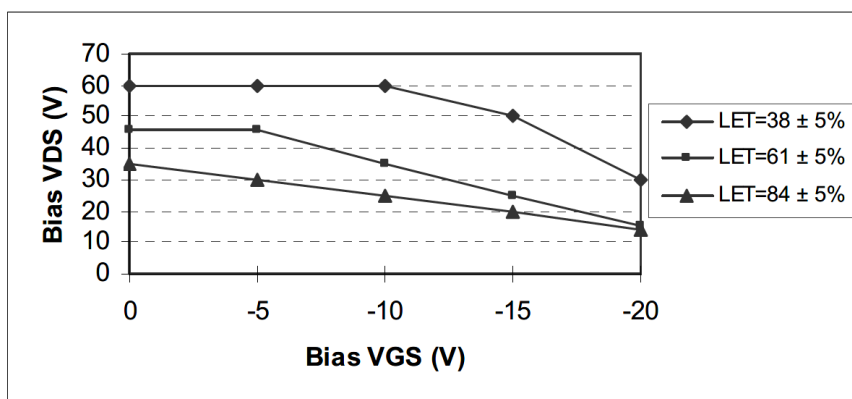
#### Device Characteristics

#### 2.4.2 Single Event Effects — Safe Operating Area

IR HiRel radiation hardened MOSFETs have been characterized in heavy ion environment for Single Event Effects (SEE). Single Event Effects characterization is illustrated in Fig. 1 and Table 7.

**Table 7 Typical Single Event Effects Safe Operating Area**

LET (MeV·cm <sup>2</sup> /mg)	Energy (MeV)	Range (μm)	V <sub>DS</sub> (V)				
			V <sub>GS</sub> = 0V	V <sub>GS</sub> = -5V	V <sub>GS</sub> = -10V	V <sub>GS</sub> = -15V	V <sub>GS</sub> = -20V
38 ± 5%	300 ± 7.5%	38 ± 7.5%	60	60	60	60	30
61 ± 5%	330 ± 7.5%	31 ± 10%	46	46	35	25	15
84 ± 5%	350 ± 10%	28 ± 7.5%	35	30	25	20	14



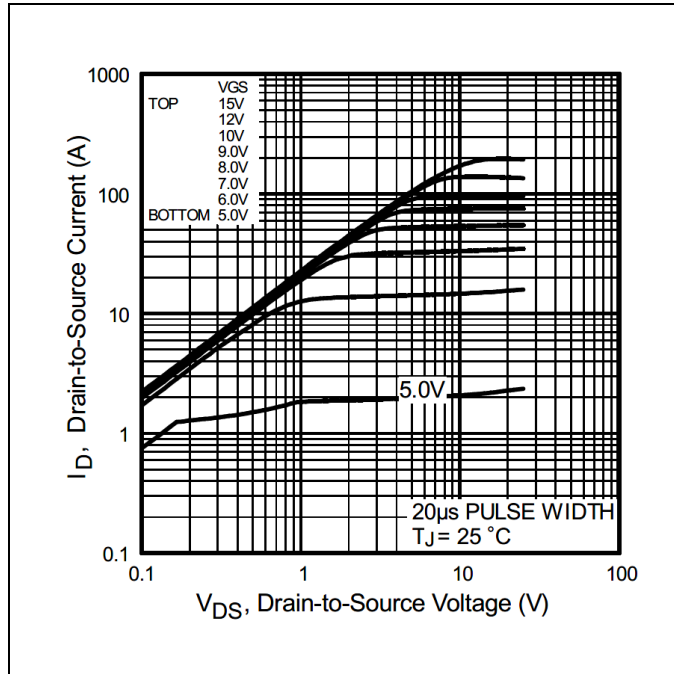
**Figure 1 Typical Single Event Effect, Safe Operating Area**

# IRHF57034 (JANSR2N7492T2)

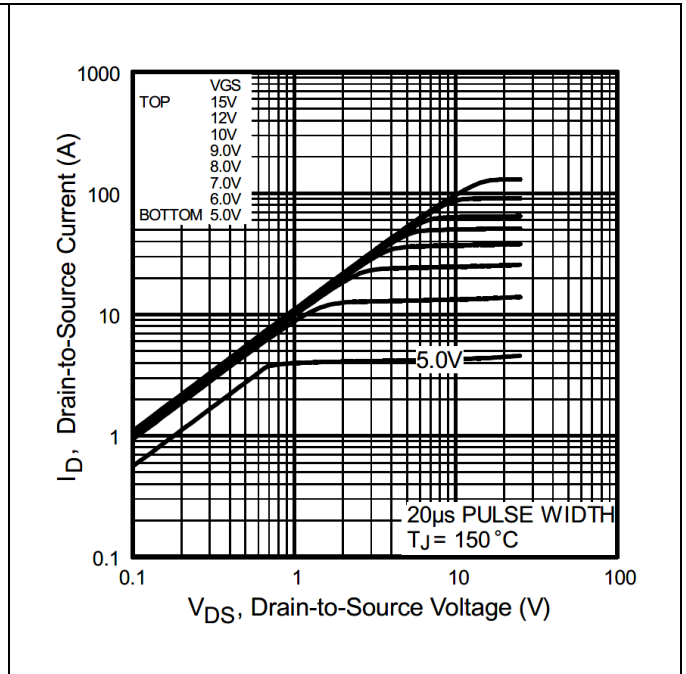
## Radiation Hardened Power MOSFET Thru-Hole (TO-39)

### Electrical Characteristics Curves (Pre-irradiation)

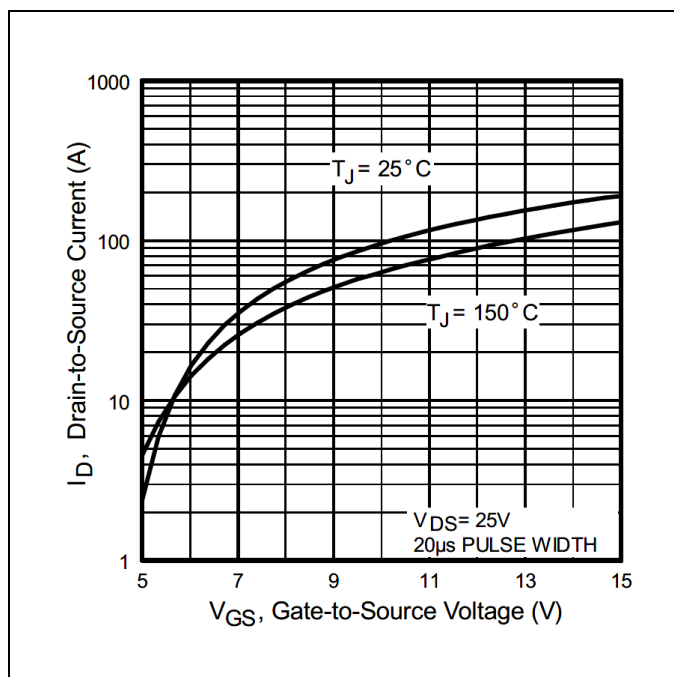
### 3 Electrical Characteristics Curves (Pre-irradiation)



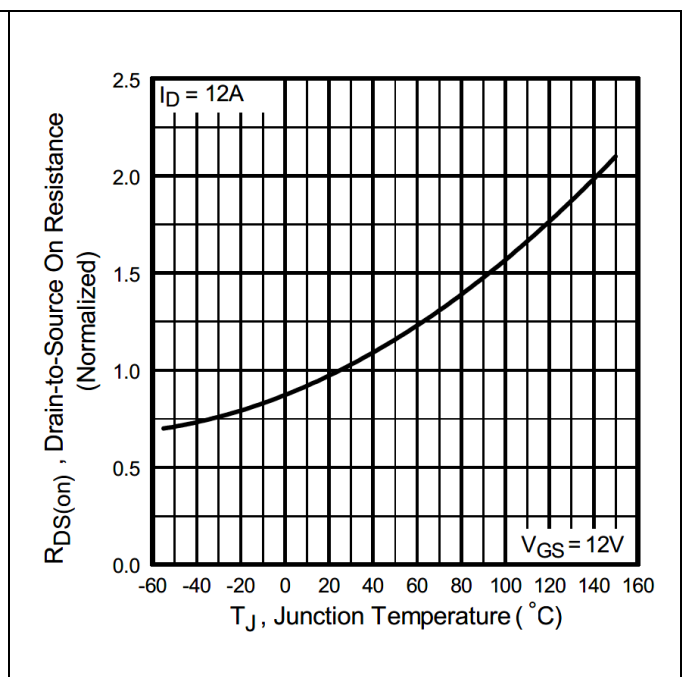
**Figure 2 Typical Output Characteristics**



**Figure 3 Typical Output Characteristics**



**Figure 4 Typical Transfer Characteristics**

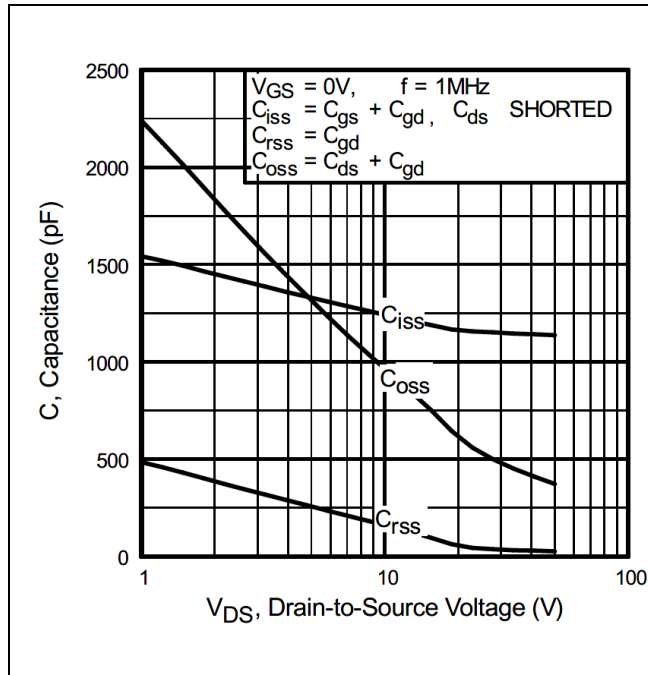


**Figure 5 Normalized On-Resistance Vs. Temperature**

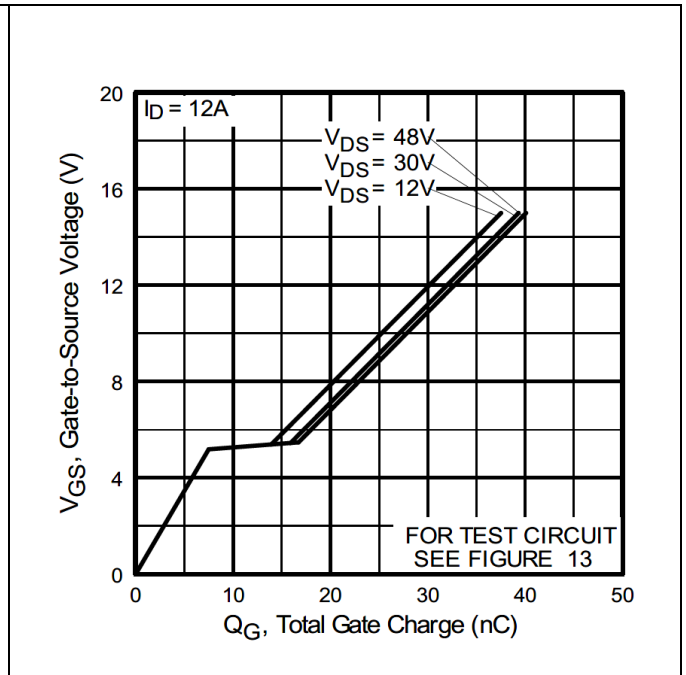
# IRHF57034 (JANSR2N7492T2)

## Radiation Hardened Power MOSFET Thru-Hole (TO-39)

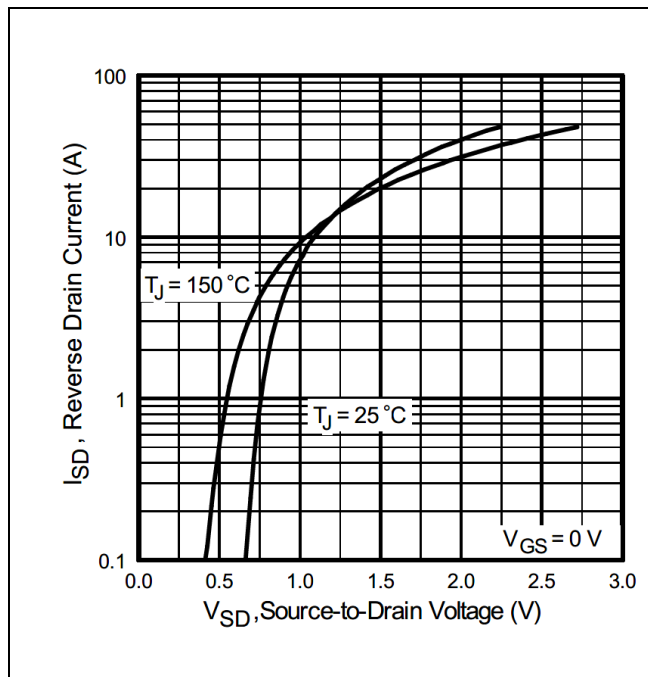
### Electrical Characteristics Curves (Pre-irradiation)



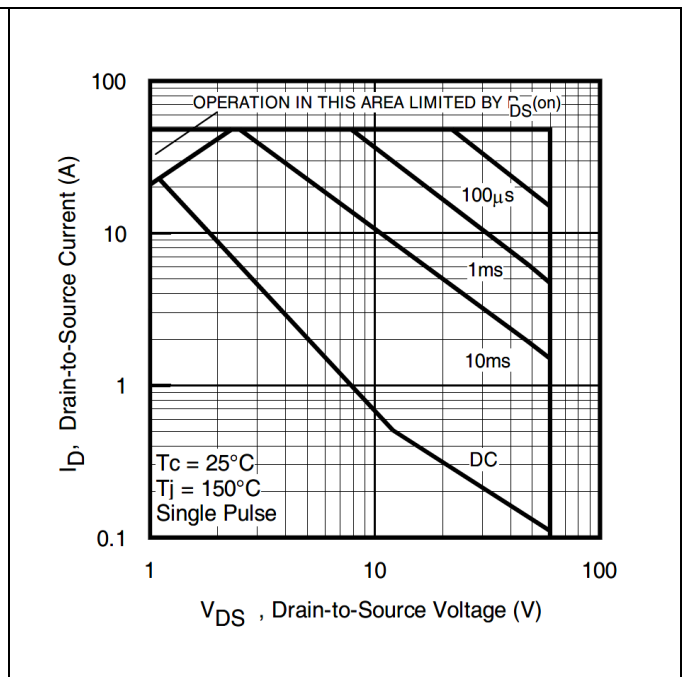
**Figure 6** Typical Capacitance Vs. Drain-to-Source Voltage



**Figure 7** Typical Gate-to-Source Voltage Vs. Typical Gate Charge



**Figure 8** Typical Source-Drain Current Vs. Diode Forward Voltage



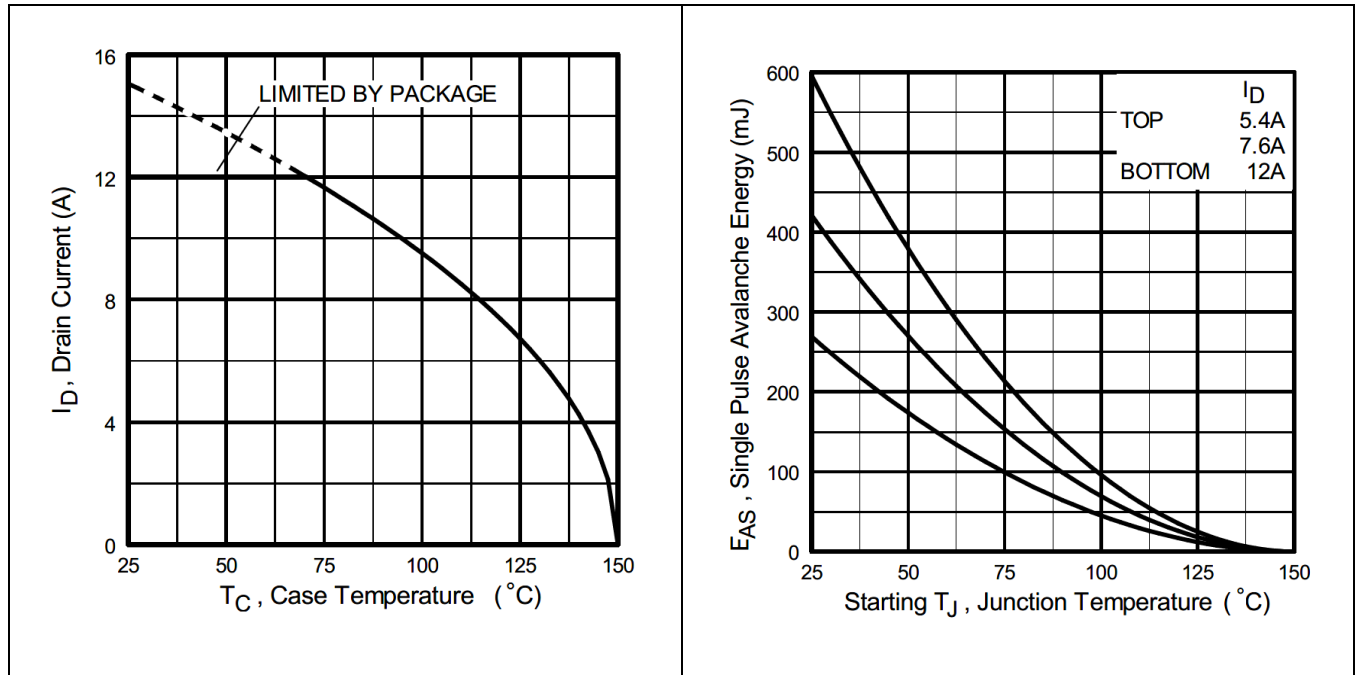
**Figure 9** Maximum Safe Operating Area



# IRHF57034 (JANSR2N7492T2)

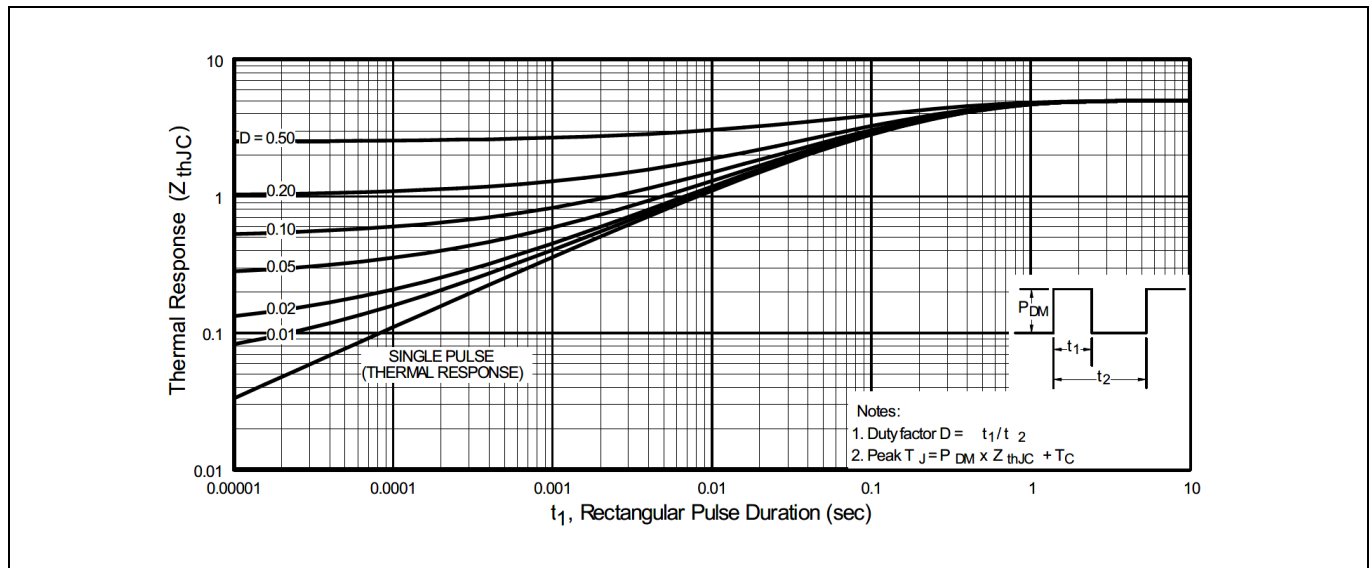
## Radiation Hardened Power MOSFET Thru-Hole (TO-39)

### Electrical Characteristics Curves (Pre-irradiation)



**Figure 10 Maximum Drain Current Vs. Case Temperature**

**Figure 11 Maximum Avalanche Energy Vs. Junction Temperature**



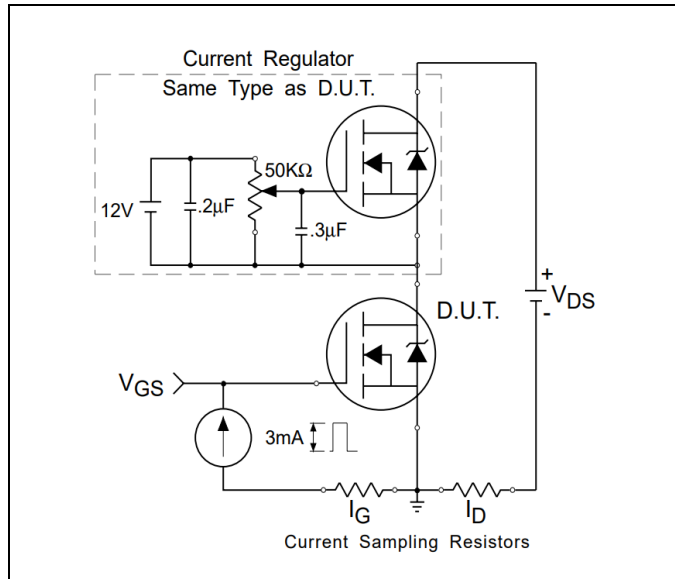
**Figure 12 Maximum Effective Transient Thermal Impedance, Junction-to-Case**

# IRHF57034 (JANSR2N7492T2)

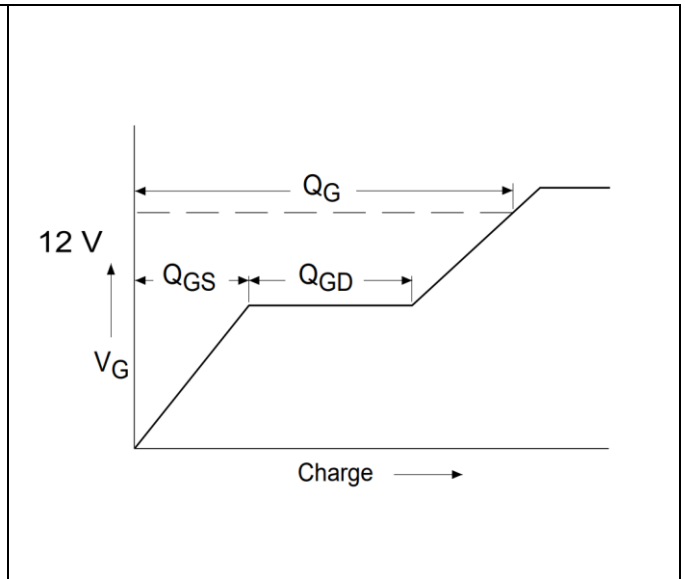
## Radiation Hardened Power MOSFET Thru-Hole (TO-39)

### Test Circuits (Pre-irradiation)

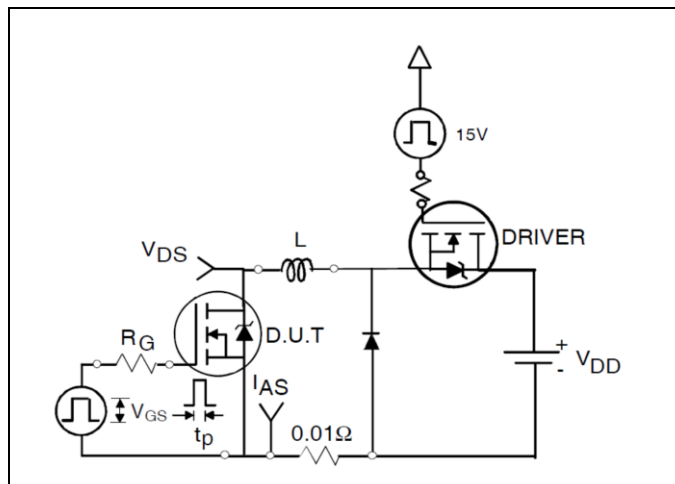
## 4 Test Circuits (Pre-irradiation)



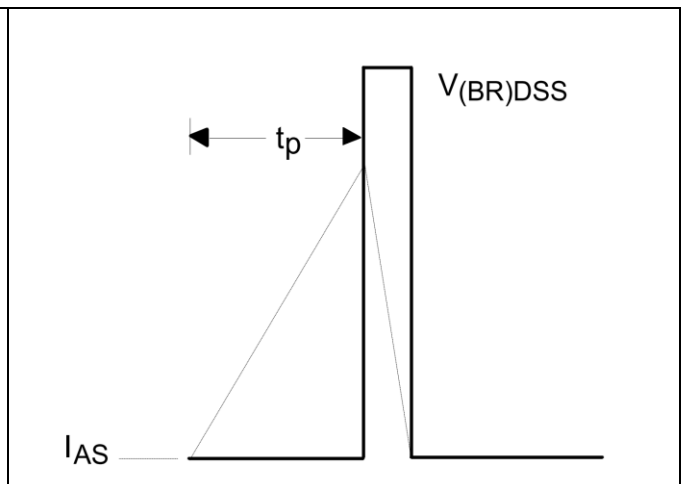
**Figure 13 Gate Charge Test Circuit**



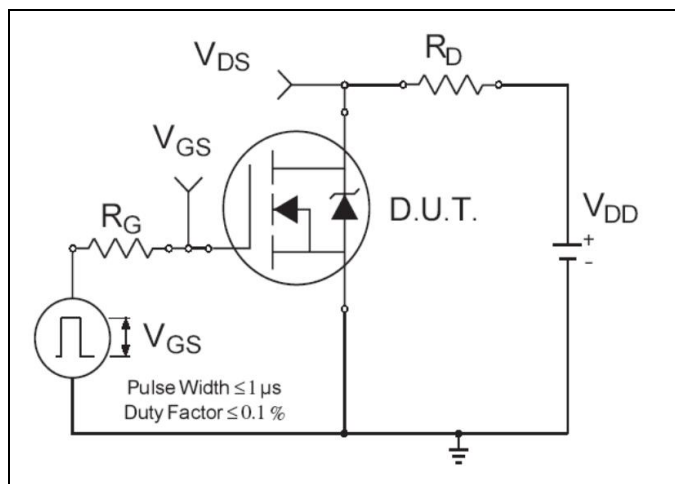
**Figure 14 Gate Charge Waveform**



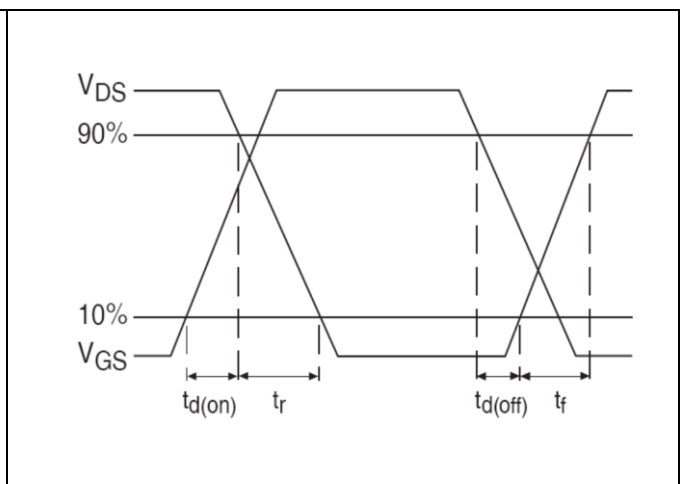
**Figure 15 Unclamped Inductive Test Circuit**



**Figure 16 Unclamped Inductive Waveform**



**Figure 17 Switching Time Test Circuit**



**Figure 18 Switching Time Waveforms**

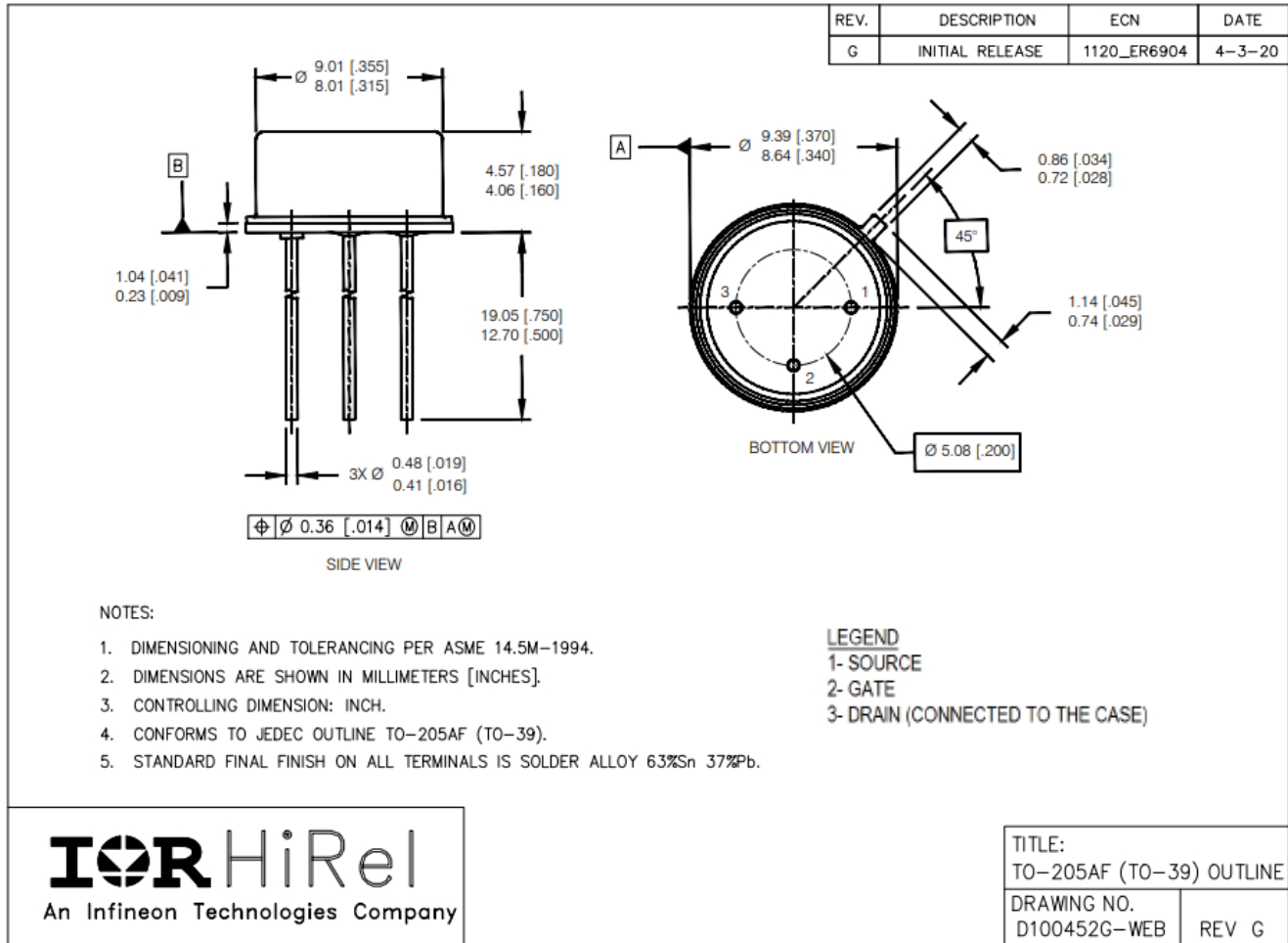
# IRHF57034 (JANSR2N7492T2)

## Radiation Hardened Power MOSFET Thru-Hole (TO-39)

### Package Outline

## 5 Package Outline

**Note:** For the most updated package outline, please see the website: [TO-39](#)



**Revision history****Revision history**

<b>Document version</b>	<b>Date of release</b>	<b>Description of changes</b>
	12/01/1999	Datasheet (PD-93791)
Rev A	07/15/2002	Updated IDSS max for 1000KRad(si)
Rev B	05/06/2004	Added QPL part number
Rev C	06/10/2004	Updated ID @ 100C
Rev D	04/27/2006	Updated from 600KRad(si) to 500KRad(si)
Rev E	10/19/2011	Updated SEE table
Rev F	05/27/2022	Updated based on ECN-1120_09018
Rev G	08/19/2025	Updated based on ECN- Z8F80801882

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